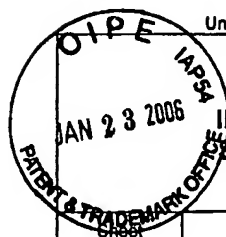


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| Application Number | 10/847,985 |
| Filing Date | August 28, 2003 |
| First Named Inventor | Patricia Beauregard Smith, et al. |
| Group Art Unit | 1746 |
| Examiner Name | Zelnab El-Arini |
| Attorney Docket No. | TI-33260 |

U.S. PATENT DOCUMENTS

| Exam. Initials [*] | Cite No. ¹ | U.S. Patent Document | | Name of Patentee or Applicant of Cited Doc. | Date of Pub. of Cited Doc. (mm-dd-yyyy) | Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear |
|--------------------------------|--------------------------|----------------------|--------------------------------------|---|---|--|
| | | Number | Kind Code ² (if known) | | | |
| ZE | AA | 2003/0104320 | A1 | Nguyen et al. | 08/05/2003 | |
| | AB | 2003/0008518 | A1 | Chang et al. | 01/09/2003 | |
| | AC | 6,107,202 | | Chiu et al. | 08/22/2000 | |
| | AD | 6,100,183 | | Lu et al. | 08/08/2000 | |
| | AE | 5,798,323 | | Honda et al. | 08/25/1998 | |
| ZE | AF | 5,843,407 | | Chang | 07/01/1997 | |
| | AG | | | | | |
| | AH | | | | | |
| | AI | | | | | |
| | AJ | | | | | |

FOREIGN PATENT DOCUMENTS

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NON PATENT LITERATURE DOCUMENTS

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|--------------------------------|--------------------------|---|----------------|
| ZE | CA | OKUDA, Seichiro, et al., "New Dry Tool after Cleaning of Low-k Dielectrics," <i>Solid State Phenomena</i> , Vol. 92, 2003, pp. 287-291. Proceedings of Ultra Clean Processing of Silicon Surfaces Conference, April 15, 2003, Diffusion and Defect Data, Solid State Data, Part B, Vaduz, LI, September 2003. | |
| ZE | CB | YANG, S.C., et al., "Process Optimization of Hydrogen Silsesquioxane (HSQ) Via Etch for 0.18um Technology and Beyond," <i>Advanced Metallization Conference 1999</i> , Orlando, Florida, September 28-30, 1999, pp. 455-459. | |
| | CC | | |
| | CD | | |
| | CE | | |
| | CF | | |
| | CG | | |
| | CH | | |
| | CI | | |
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| Examiner Signature | EL-Arini | Date Considered | 3/10/06 |
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